

Substrate Resistance Extraction Using a Multi-Domain Surface Integral Formulation

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Abstract—In order to assess and optimize layout strategies for minimizing substrate noise, it is necessary to have fast and accurate techniques for computing contact coupling resistances associated with the substrate. In this talk, we describe an extraction method capable of full-chip analysis which combines modest geometric approximations, a novel integral formulation, and an FFT-accelerated preconditioned iterative method.

[Full Text Not Available]